



MOOV

1-Supplier	
Name	HITACHI
2-Equipement Type	
Description	S-5000
3-Process	
Process type	FE-SEM
4-Wafer Type	
Wafer specification	-
5-Layout configuration	
Specific Layout defintion	Standard
6-CE Compliance	
7-Mainframe configuration	
Platform	
configuration	
Position 1	Body
1. Resolution	0.6nm (6Å) (acceleration voltage 30kV) However, it is confirmed at an edge interval of 0.3 mm at 500,000 times-with a sample for resolution measurement. 30 nm (30 Å) (acceleration voltage 1 kV, in HIGH-Z mode) However, it is confirmed at an edge interval of 0.3 mm at a magnification of 100,000 times-with a sample for resolution measurement.
2.magnification	× 30 to × 500 times (low magnification mode) × 250 to × 800,000 times (high magnification mode)
3. Electro-optical system	
Electron gun	Cold cathode field emission electron gun, built-in butler type electrostatic lens Built-in anode heater
Acceleration voltage	0.5 to 30 kV (0.1 kV step)
Lens system	3-stage electromagnetic lens reduction system
Stigma toll	8-pole electromagnetic system (X, Y)
Deflection coil	Two-stage electrode deflection method
Objective diaphragm	Movable aperture (4 holes can be switched and finely adjusted from outside the vacuum, Squeeze heating can be turned on and off)
4 Sample fine movement device	
(1) Method	Side entry method
(2) Movement range	X = ± 3.5 mm, Y = ± 2 mm T = ± 40 ° When the backscattered electron detector is inserted, it is limited to ± ± 8 °
(3) Stage control	Movement speed (X, Y) is switched in 3 steps (FAST, MED, SLOW) Magnification link
(4) Sample size	9.5mm x 5mm x 2.4mmH (maximum) <When using standard holder>

	<i>9.5mm x 5mm x 4.4mmH (maximum) <When using standard holder and in HIGH-Z mode</i>
(5) Sample exchange	<i>Airlock method</i>
5. Detector	
(1) Secondary electron detector	
6. display	
(1) Type of image	<i>Secondary electron image</i>
(2) Display method	<i>Still image display with built-in image memory (total scanning speed)</i>
(3) Image memory	<i>Configuration: 512 x 512 pixel buffer memory 1 side + 1024 x 1024 Pixel high-definition memory 2 sides Function: • Photographing of high-definition (1024 x 1024) images Real-time TV display of slow scan image (all scan speeds) S / N improvement by averaging TV scan images Image integration on TV and first scan (1024 times Max) Memory image contrast conversion (21 types of conversion curves built-in) Real-time histogram (signal strength analysis) display 4-split image display</i>
9-Chemical Solution configuration	
10- Workstation hardware configuration	
11-System software/ automation configuration	
12-Electrical	
13-Ancillaries	
14- Hook-up connexion / Specific requirement	
15-Options	
17- Target process performances	